

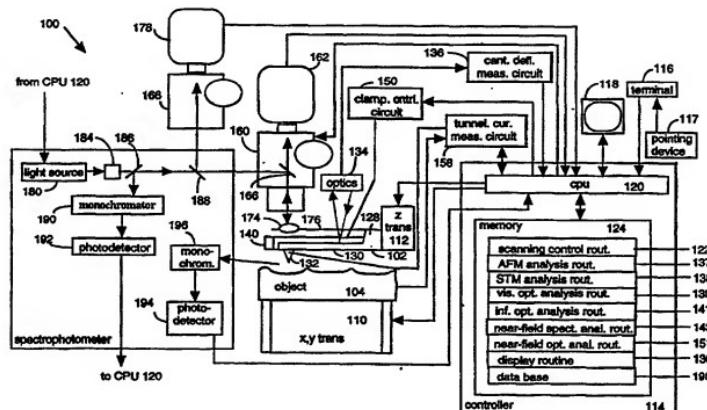


INTERNATIONAL APPLICATION PUBLISHED UNDER THE PATENT COOPERATION TREATY (PCT)

(51) International Patent Classification 6: G01N 23/22, H01J 3/14	A1	(11) International Publication Number: WO 96/03641
		(43) International Publication Date: 8 February 1996 (08.02.96)

(21) International Application Number: PCT/US95/09553	(81) Designated States: AM, AT, AU, BB, BG, BR, BY, CA, CH, CN, CZ, DE, DK, EE, ES, FI, GB, GE, HU, IS, JP, KE, KG, KP, KR, KZ, LK, LR, LT, LU, LV, MD, MG, MN, MW, MX, NO, NZ, PL, PT, RO, RU, SD, SE, SG, SI, SK, TJ, TM, TT, UA, UG, US, UZ, VN, European patent (AT, BE, CH, DE, DK, ES, FR, GB, GR, IE, IT, LU, MC, NL, PT, SE), OAPI patent (BF, BJ, CF, CG, CI, CM, GA, GN, ML, MR, NE, SN, TD, TG), ARIPO patent (KE, MW, SD, SZ, UG).
(22) International Filing Date: 28 July 1995 (28.07.95)	
(30) Priority Data: 08/281,883 28 July 1994 (28.07.94) US 08/412,380 29 March 1995 (29.03.95) US	
(60) Parent Applications or Grants	
(63) Related by Continuation	
US Filed on 08/281,883 (CIP) US Filed on 28 July 1994 (28.07.94) US Filed on 08/412,380 (CIP) US Filed on 29 March 1995 (29.03.95)	Published With international search report.
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(54) Title: SCANNING PROBE MICROSCOPE ASSEMBLY



(57) Abstract

A scanning probe microscope assembly (100) is disclosed that has an atomic force measurement (AFM) mode (137), a scanning tunneling measurement (STM) mode (138), a near-field spectrometry mode (113), a near-field optical mode (151), and a hardness testing mode for examining an object (104).